

STB130NH02L

N-CHANNEL 24V - 0.0034 Ω - 120A D²PAK STripFET™ III POWER MOSFET FOR DC-DC CONVERSION

TYPE	V _{DSS}	R _{DS(on)}	I _D
STB130NH02L	24 V	< 0.0044 Ω	90 A(2)

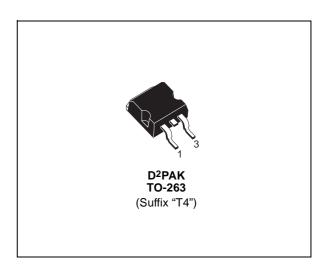
- TYPICAL $R_{DS}(on) = 0.0034 \Omega @ 10 V$
- TYPICAL $R_{DS}(on) = 0.005 \Omega @ 5 V$
- R_{DS(ON)} * Qg INDUSTRY's BENCHMARK
- CONDUCTION LOSSES REDUCED
- SWITCHING LOSSES REDUCED
- LOW THRESHOLD DEVICE
- SURFACE-MOUNTING D²PAK (TO-263)
 POWER PACKAGE IN TUBE (NO SUFFIX) OR IN TAPE & REEL (SUFFIX "T4")

DESCRIPTION

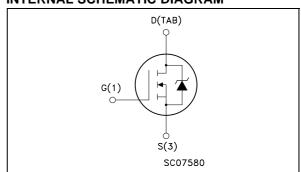
The STB130NH02L utilizes the latest advanced design rules of ST's proprietary STripFET™ technology. It is ideal in high performance DC-DC converter applications where efficiency is to be achieved at very high output currents.

APPLICATIONS

- SYNCHRONOUS RECTIFICATIONS FOR TELECOM AND COMPUTER
- OR-ING DIODE



INTERNAL SCHEMATIC DIAGRAM



ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V _{spike(1)}	Drain-source Voltage Rating	30	V
V _{DS}	Drain-source Voltage (V _{GS} = 0)	24	V
V _{DGR}	Drain-gate Voltage ($R_{GS} = 20 \text{ k}\Omega$)	24	V
V _{GS}	Gate- source Voltage	± 20	V
I _D (2)	Drain Current (continuous) at T _C = 25°C	90	Α
I _D (2)	Drain Current (continuous) at T _C = 100°C	90	А
I _{DM} (3)	Drain Current (pulsed)	360	А
P _{tot}	Total Dissipation at T _C = 25°C	150	
	Derating Factor	1	W/°C
E _{AS} (4)	Single Pulse Avalanche Energy	900	mJ
T _{stg}	Storage Temperature	-55 to 175	
Tj	Max. Operating Junction Temperature	-55 (0 1/5	

February 2003 1/11

STB130NH02L

THERMAL DATA

Rthj-case Thermal Resistance Junction-case Ma Rthj-amb Thermal Resistance Junction-ambient Ma To Maximum Lead Temperature For Soldering Purpose	-	°C/W
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ELECTRICAL CHARACTERISTICS ($T_{CASE} = 25~^{\circ}C$ UNLESS OTHERWISE SPECIFIED) OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source Breakdown Voltage	$I_D = 25 \text{ mA}, V_{GS} = 0$	24			V
I _{DSS}	Zero Gate Voltage Drain Current (V _{GS} = 0)	V _{DS} = 20 V V _{DS} = 20 V T _C = 125°C			1 10	μA μA
I _{GSS}	Gate-body Leakage Current (V _{DS} = 0)	V _{GS} = ± 20 V			±100	nA

ON (5)

	Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Unit
Ī	V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$	I _D = 250 μA	1			V
	R _{DS(on)}	Static Drain-source On Resistance	V _{GS} = 10 V V _{GS} = 5 V	I _D = 45 A I _D = 22.5 A		0.0034 0.005	0.0044 0.008	Ω Ω

DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g _{fs} (5)	Forward Transconductance	$V_{DS} = 10 \text{ V}$ $I_{D} = 45 \text{ A}$		55		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 15V f = 1 MHz V_{GS} = 0$		4450 1126 141		pF pF pF
R _G	Gate Input Resistance	f = 1 MHz Gate DC Bias = 0 Test Signal Level = 20 mV Open Drain		1.6		Ω

ELECTRICAL CHARACTERISTICS (continued)

SWITCHING ON

Symbol	Parameter Test Conditions		Min.	Тур.	Max.	Unit
t _{d(on)} t _r	Turn-on Delay Time Rise Time	$\begin{array}{ccc} V_{DD} = 10 \text{ V} & I_D = 45 \text{ A} \\ R_G = 4.7 \; \Omega & V_{GS} = 10 \text{ V} \\ \text{(Resistive Load, Figure 3)} \end{array}$		14 224		ns ns
Q _g Q _{gs} Q _{gd}	Total Gate Charge Gate-Source Charge Gate-Drain Charge	V _{DD} =10 V I _D =90 A V _{GS} =10 V		69 13 9	93	nC nC nC
Q _{oss} (6)	Output Charge	V _{DS} = 16 V V _{GS} = 0 V		27		nC
Q _{gls} (7)	Third-quadrant Gate Charge	V _{DS} < 0 V V _{GS} = 10 V		64		nC

SWITCHING OFF

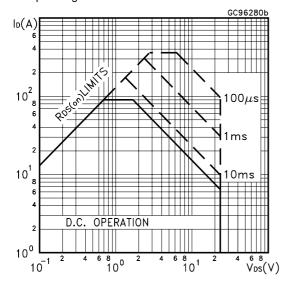
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(off)}	Turn-off Delay Time Fall Time	$\begin{aligned} &V_{DD} = 10 \text{ V} & I_{D} = 45 \text{ A} \\ &R_{G} = 4.7\Omega, & V_{GS} = 10 \text{ V} \\ &(\text{Resistive Load, Figure 3}) \end{aligned}$		69 40	54	ns ns

SOURCE DRAIN DIODE

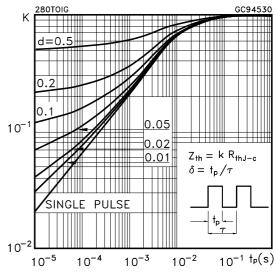
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain Current Source-drain Current (pulsed)				90 360	A A
V _{SD} (5)	Forward On Voltage	I _{SD} = 45 A V _{GS} = 0			1.3	V
t _{rr} Q _{rr} I _{RRM}	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD} = 90 \text{ A}$ di/dt = $100 \text{A}/\mu \text{s}$ $V_{DD} = 15 \text{ V}$ $T_j = 150^{\circ}\text{C}$ (see test circuit, Figure 5)		47 58 2.5		ns nC A

⁽¹⁾ Garanted when external Rg=4.7 Ω and $t_f < t_{fmax}$. (2) Value limited by wire bonding (3) Pulse width limited by safe operating area. (4) Starting $T_j = 25$ °C, $I_D = 45$ A, $V_{DD} = 10$ V

Safe Operating Area

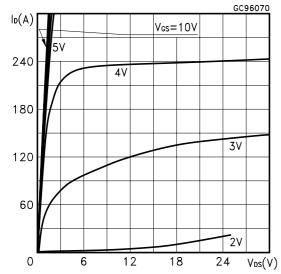


Thermal Impedance

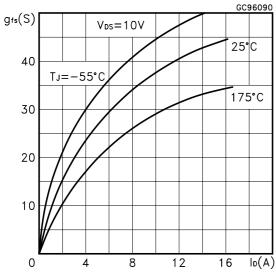


⁽⁵⁾ Pulsed: Pulse duration = 300 μ s, duty cycle 1.5 %. (6) $Q_{OSS} = C_{OSS}^* \Delta \ V_{in}$, $C_{OSS} = C_{gd} + C_{ds}$. See Appendix A (7) Gate charge for synchronous operation

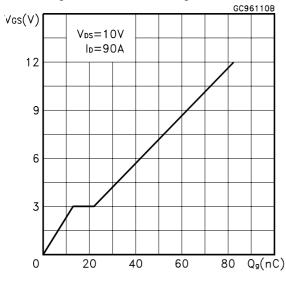
Output Characteristics



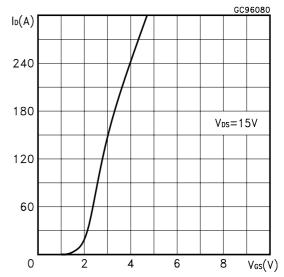
Transconductance



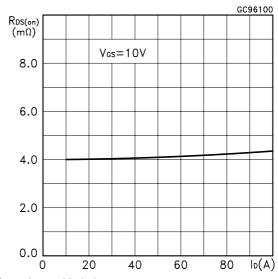
Gate Charge vs Gate-source Voltage



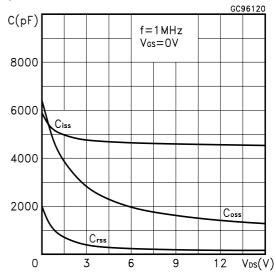
Transfer Characteristics



Static Drain-source On Resistance

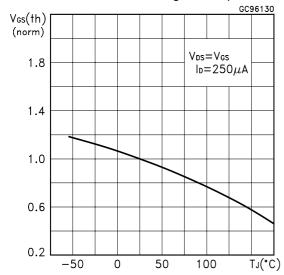


Capacitance Variations

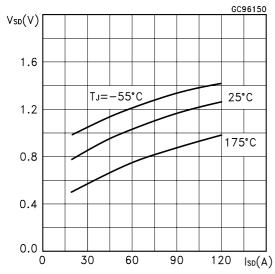


STB130NH02L

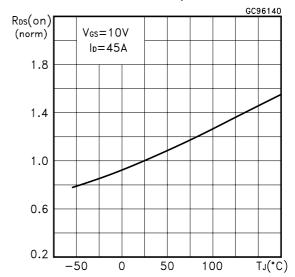
Normalized Gate Threshold Voltage vs Temperature



Source-drain Diode Forward Characteristics



Normalized on Resistance vs Temperature



Normalized Breakdown Voltage vs Temperature

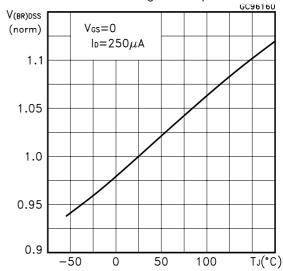


Fig. 1: Unclamped Inductive Load Test Circuit

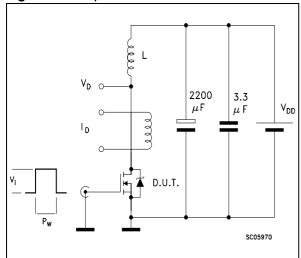


Fig. 3: Switching Times Test Circuits For Resistive Load

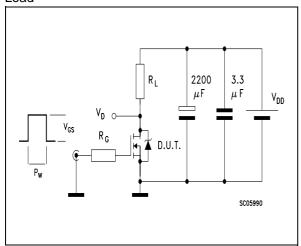


Fig. 5: Test Circuit For Inductive Load Switching And Diode Recovery Times

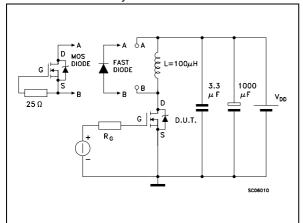


Fig. 2: Unclamped Inductive Waveform

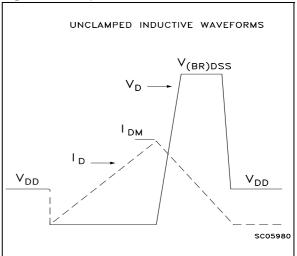
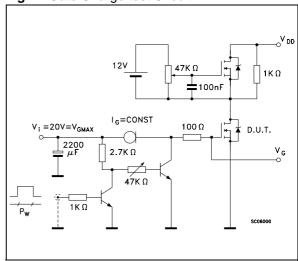
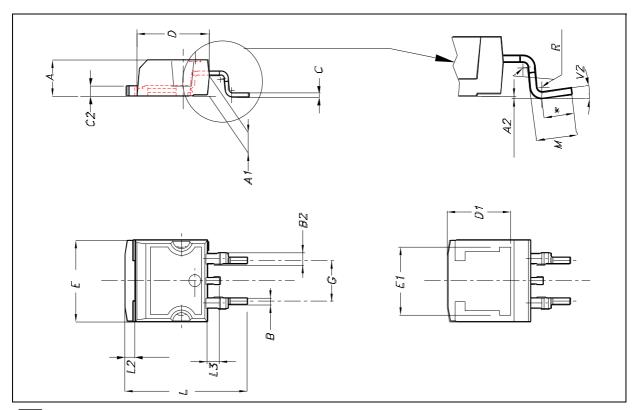


Fig. 4: Gate Charge test Circuit



D2PAK MECHANICAL DATA

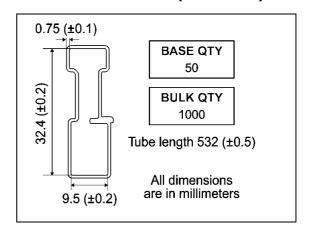
DIM.		mm.			inch.	
DINI.	MIN.	TYP.	MAX.	MIN.	TYP.	TYP.
Α	4.4		4.6	0.173		0.181
A 1	2.49		2.69	0.098		0.106
A2	0.03		0.23	0.001		0.009
В	0.7		0.93	0.028		0.037
B2	1.14		1.7	0.045		0.067
С	0.45		0.6	0.018		0.024
C2	1.21		1.36	0.048		0.054
D	8.95		9.35	0.352		0.368
D1		8			0.315	
E	10		10.4	0.394		0.409
E1		8.5			0.334	
G	4.88		5.28	0.192		0.208
L	15		15.85	0.591		0.624
L2	1.27		1.4	0.050		0.055
L3	1.4		1.75	0.055		0.069
М	2.4		3.2	0.094		0.126
R		0.4			0.015	
V2	0°		8°	0°		8°



D2PAK FOOTPRINT

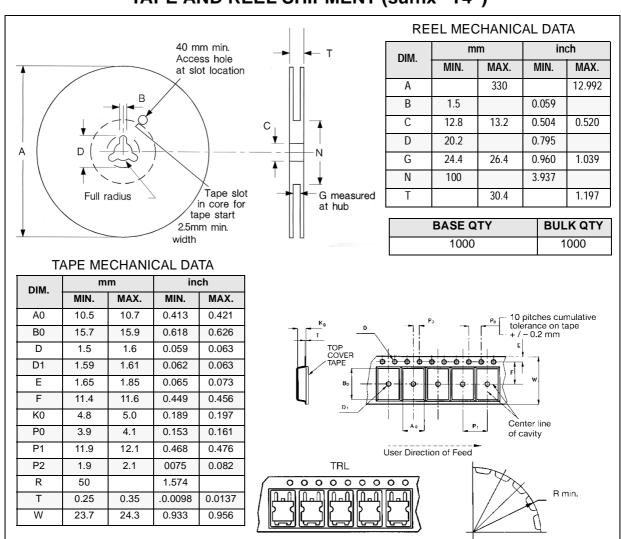
12.20 12.20 12.20 13.50 All dimensions are in millimeters

TUBE SHIPMENT (no suffix)*



Bending radius

TAPE AND REEL SHIPMENT (suffix "T4")*



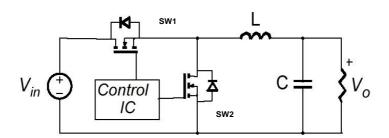
^{*} on sales type

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√7

FEED DIRECTION_

APPENDIX A Buck Converter: Power Losses Estimation



The power losses associated with the FETs in a Synchronous Buck converter can be estimated using the equations shown in the table below. The formulas give a good approximation, for the sake of performance comparison, of how different pairs of devices affect the converter efficiency. However a very important parameter, the working temperature, is not considered. The real device behavior is really dependent on how the heat generated inside the devices is converted to allow for a safer working junction temperature.

The low side (SW2) device requires:

- ullet Very low $R_{DS(on)}$ to reduce conduction losses
- ullet Small Q_{gls} to reduce the gate charge losses
- Small Coss to reduce losses due to output capacitance
- Small Q_{rr} to reduce losses on SW₁ during its turn-on
- The C_{gd}/C_{gs} ratio lower than V_{th}/V_{gg} ratio especially with low drain to source voltage to avoid the cross conduction phenomenon;

The high side (SW1) device requires:

- ullet Small R_g and L_s to allow higher gate current peak and to limit the voltage feedback on the gate
- Small Q_g to have a faster commutation and to reduce gate charge losses
- Low R_{DS(on)} to reduce the conduction losses.

		High Side Switch (SW1)	Low Side Switch (SW2)
Pconduction		$R_{DS(on)SW1} * I_L^2 * d$	$R_{DS(on)SW2} * I_L^2 * (1-d)$
Pswitching		$V_{\text{in}} * (Q_{\text{gsth(SW1)}} + Q_{\text{gd(SW1)}}) * f * \frac{I_L}{I_g}$	Zero Voltage Switching
P_{diode}	Recovery	Not Applicable	¹ V _{in} *Q _{rr(SW2)} * f
	Conduction	Not Applicable	$V_{\text{f(SW2)}} * I_{\text{L}} * t_{\text{deadtime}} * f$
$P_{\text{gate}(Q_G)}$		$Q_{g(SW1)}*V_{gg}*f$	$Q_{gls(SW2)}*V_{gg}*f$
P _{Qoss}		$\frac{V_{in} *Q_{oss(SWI)} *f}{2}$	$\frac{V_{in} *Q_{oss(SW2)} *f}{2}$

Parameter	Meaning
d	Duty-cycle
Q _{gsth}	Post threshold gate charge
$Q_{ m gls}$	Third quadrant gate charge
Pconduction	On state losses
Pswitching	On-off transition losses
Pdiode	Conduction and reverse recovery diode losses
Pgate	Gate drive losses
P _{Qoss}	Output capacitance losses

¹ Dissipated by SW1 during turn-on

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